

Lecture 7: Bias, Var, Model Complexity

To precisely discuss evaluation need to keep track of what is random and what is fixed.

Consider training data $(\underline{X}_n, Y_n) \stackrel{iid}{\sim} p$

Let $T = \{(\underline{X}_n, Y_n)\}_{n=1}^N$ be training data

↑ this is random

We use this training data to build a model

$$\hat{f} = \hat{f}_T$$

↑ also random

Let \underline{X}_0, Y_0 be indep (from training) sample from p

If M is some perf. metric (like L)

then let

$$\text{Err}_T = \mathbb{E}[M(Y_0, \hat{f}(\underline{X}_0)) | T]$$

what we'd really like to estimate →

how close $\hat{f}(\underline{X}_0)$ is to Y_0

↑ T is fixed

= given specific T what is expected err. if we predict using \hat{f} on independent sample \underline{X}_0, Y_0

= gen. perf. using this training data T

This is quite difficult in practice to estimate.

Instead, typically easier to estimate

$$\begin{aligned} \text{Err} &= E_T[\text{Err}_T] \\ &= E[M(y_0, \hat{f}(x_0))] \end{aligned}$$

= exp. gen. perf. over new samples
AND
over all possible training data

= exp. perf. of my model building process

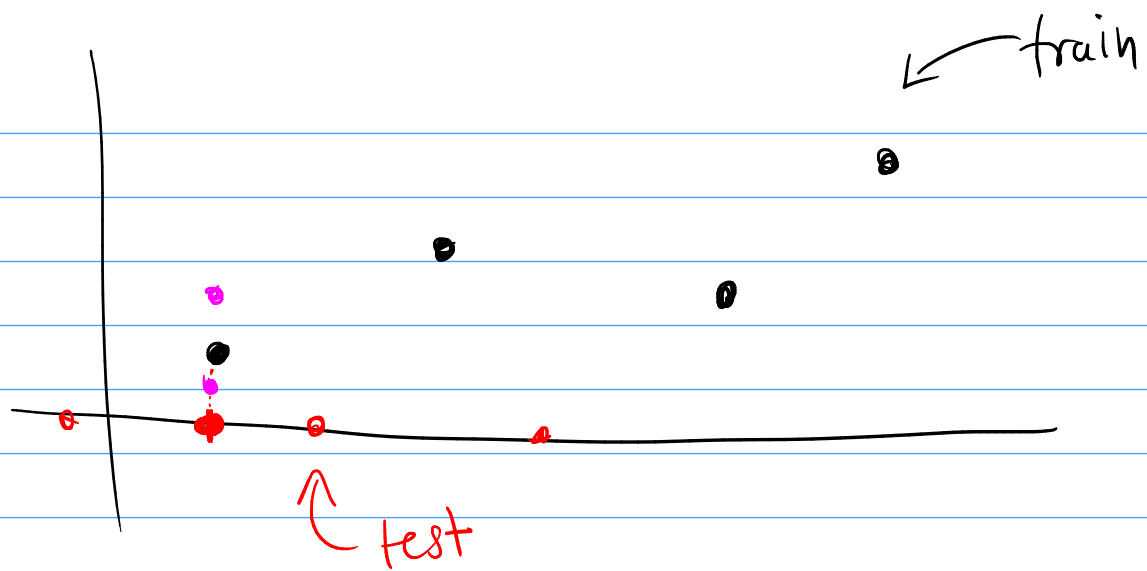
Let $\overline{\text{err}}$ = training error = $\frac{1}{N} \sum_n M(y_n, \hat{f}(x_n))$

Typically $\overline{\text{err}} < \text{Err}_T$ b/c we overfit
↑ both calc. w/ fixed training

Parts of the problem

① \tilde{x}_0 is random but x_n s are fixed
So new \tilde{x}_0 may not be exactly the same as x_n s.

② y^0 is random so might not match y_n s.



To simplify analysis, consider only Y^o being random and define the in-sample error as

$$Err_{in} = \frac{1}{N} \sum_n E[M(Y_o, \hat{f}(x_n)) | T]$$

↑ like Err_T but fixing \underline{x}_n at train pts
 ↑ fixed at train pts

let the optimism be

$$op = Err_{in} - \overline{err}$$

↑ random (deps on Y^o)
 in sample - training

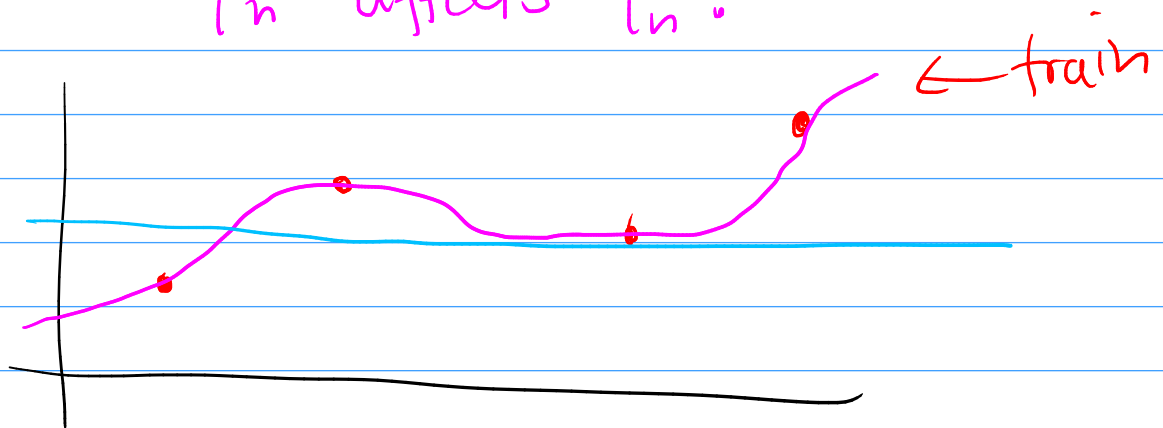
Typically $op > 0$ as \overline{err} underestimates Err_{in}
 and if

$$\omega = E[op]$$

= avg optimism

Generally,
$$\omega = \frac{2}{N} \sum_n \text{Cov}(\hat{Y}_n, Y_n)$$

So ω is rel. to the avg. amt that Y_n affects \hat{Y}_n .



So
$$E[\text{Err}_{in}] = E[\overline{\text{err}}] + \omega$$

In some cases one can directly estimate ω as $\hat{\omega}$ in which case

est. of $\text{Err}_{in} = \overline{\text{err}} + \hat{\omega}$

\uparrow know \uparrow estimate

e.g. If we assume $Y = f(\underline{X}) + \epsilon$
 where $\epsilon \perp \underline{X}, Y$ and $E\epsilon = 0, \text{Var}(\epsilon) = \sigma^2$

covs.
 \swarrow

then
$$\omega = \frac{2P}{N} \sigma^2$$

and so
$$\hat{\omega} = \frac{2P}{N} \hat{\sigma}^2$$

$$\text{est. of in-sample err} = \overline{\text{err}} + \frac{2p}{N} \hat{\sigma}^2$$



Many ways to do this dep. on assumptions,
 C_p , AIC, BIC, adj. R^2

Hold on, this only estimates in-sample err —
 doesn't take into account randomness in \underline{X}_0 .

Yes, but often it's good enough for model selection,
 b/c it still allows me to eval. rel. perf.
 among models.

If want to est. gen. perf. still need to
 do some kind of x-validation.

↳ estimating Err
 not Err_T